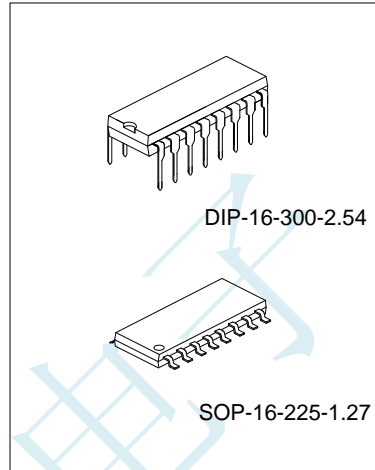


HIGH VOLTAGE AND HIGH CURRENT DARLINGTON TRANSISTOR ARRAY

DESCRIPTION

The ULN2003 is a monolithic high voltage and high current Darlington transistor arrays. It consists of seven NPN darlington pairs that features high-voltage outputs with common-cathode clamp diode for switching inductive loads. The collector-current rating of a single darlington pair is 500mA. The darlington pairs may be parrleled for higher current capability. Applications include relay drivers,hammer drivers, lampdrivers,display drivers(LED gas discharge),line drivers, and logic buffers.

The ULN2003 has a 2.7kΩ series base resistor for each darlington pair for operation directly with TTL or 5V CMOS devices.



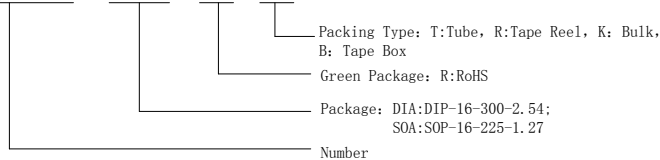
FEATURES

- * 500mA rated collector current(Single output)
- * High-voltage outputs: 50V
- * Inputs compatibale with various types of logic.
- * Relay driver application

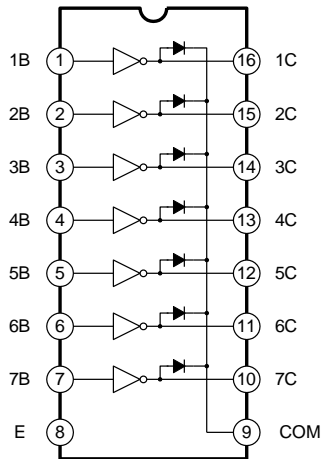
ORDERING INFORMATION

Ordering Number	Package	Print Number	Free	Packing
ULN2003-DIA-R-T	DIP-16-300-2.54	ULN2003	RoHS	Tube
ULN2003-SOA-R-T	SOP-16-225-1.27	ULN2003	RoHS	Tube
ULN2003-SOA-R-R	SOP-16-225-1.27	ULN2003	RoHS	Tape Reel

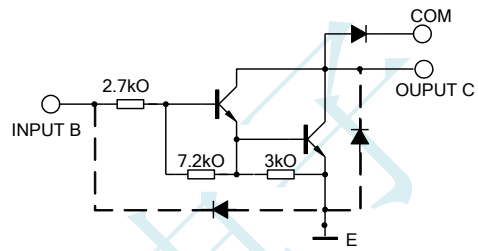
ULN2003 - DIA - R - T



LOGIC DIAGRAM



SCHEMATIC(EACH DARLINGTON PAIR)



ABSOLUTE MAXIMUM RATINGS (Ta=25°C)

Characteristic	Symbol	Value	Unit
Collector-Emitter Voltage	VCE	50	V
Input Voltage	VI	30	V
Peak Collector Current	Io	500	mA
Total Emitter-terminal	IOK	500	mA
Power Dissipation	Pd	(DIP-16)1.47 (SOP-16)1.25(Note2)	W
Operating Temperature	Topr	-20~ +85	°C
Storage Temperature	Tstg	-65 ~ +150	°C

Note: 1. All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.

2. On PCB

ELECTRICAL CHARACTERISTICS ($T_a=25^{\circ}\text{C}$, unless otherwise specified)

Characteristic	Test Figure	Symbol	Test Conditions	Min	Typ	Max	Units
On-state Input Voltage	6	$V_{I(ON)}$	$V_{CE}=2\text{V}, I_c=200\text{mA}$			2.4	V
			$V_{CE}=2\text{V}, I_c=250\text{mA}$			2.7	
			$V_{CE}=2\text{V}, I_c=300\text{mA}$			3	
Collector-Emitter Saturation Voltage	5	$V_{CE(SAT)}$	$I_l=250\mu\text{A}, I_c=100\text{mA}$		0.9	1.1	V
			$I_l=350\mu\text{A}, I_c=200\text{mA}$		1	1.3	
			$I_l=500\mu\text{A}, I_c=350\text{mA}$		1.2	1.6	
Collector Cutoff Current	1	I_{CEX}	$V_{CE}=50\text{V}, I_l=0$			50	μA
	2		$V_{CE}=50\text{V}, I_l=0, T_a=70^{\circ}\text{C}$			100	
Clamp Forward Voltage	8	V_F	$I_F=350\text{mA}$		1.7	2	V
Off-state Input Current	3	$I_{I(OFF)}$	$I_C=500\mu\text{A}, T_a=70^{\circ}\text{C}$	50	65		μA
Input Current	4	I_I	$V_I=3.85\text{V}$		0.95	1.35	mA
Clamp Reverse Current	7	I_R	$V_R=50\text{V}$			50	μA
			$V_R=50\text{V}, T_a=70^{\circ}\text{C}$			100	
Input Capacitance	--	C_I	$V_I=0, f=1\text{MHz}$		15	25	pF
Propagation delay time, low-to-high-level output	9	t_{PLH}			0.25	1	μs
Propagation delay time, high-to-low-level output	9	t_{PHL}			0.25	1	μs
High-level output Voltage after switching	10	V_{OH}	$V_s=50\text{V}, I_o=300\text{mA}$	V_s-20			mV

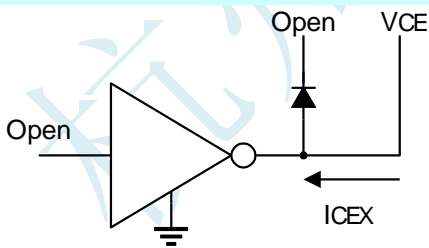
TEST CIRCUITS

Figure 1 ICEX Test Circuit

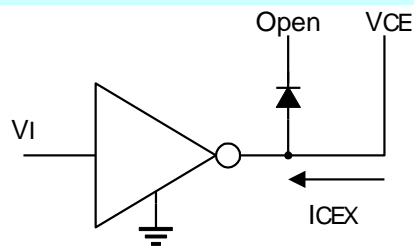


Figure 2 ICEX Test Circuit

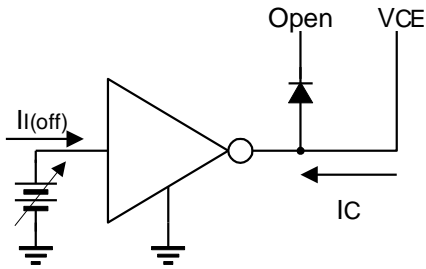


Figure 3 II(off) Test Circuit

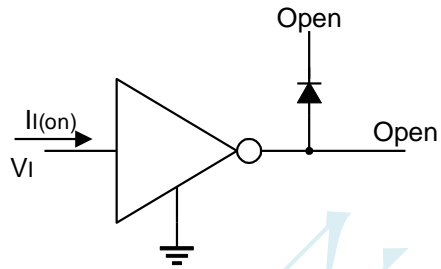


Figure 4 II(on) Test Circuit

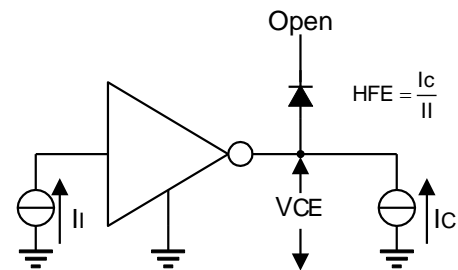


Figure 5 HFE, VCE(sat) Test Circuit

Note: II is fixed for measuring VCE(sat), variable for measuring HFE.

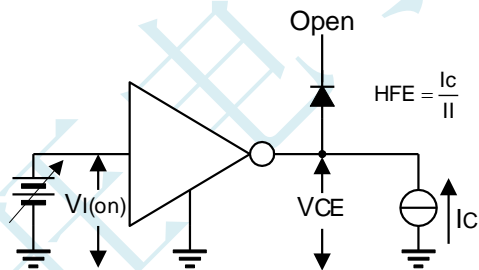


Figure 6 VI(on) Test Circuit

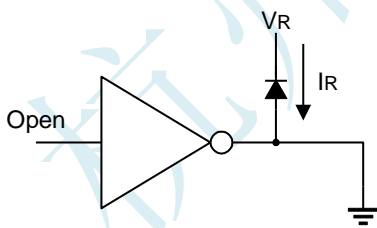


Figure 7 IR Test Circuit

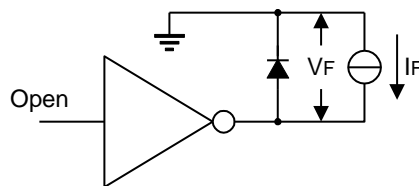


Figure 8 VF Test Circuit

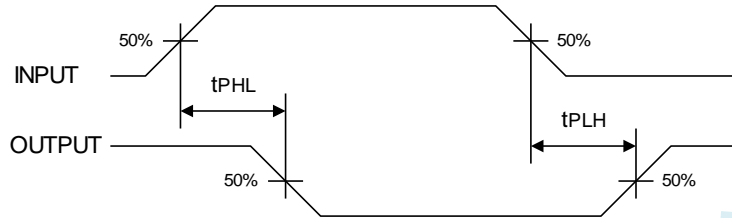
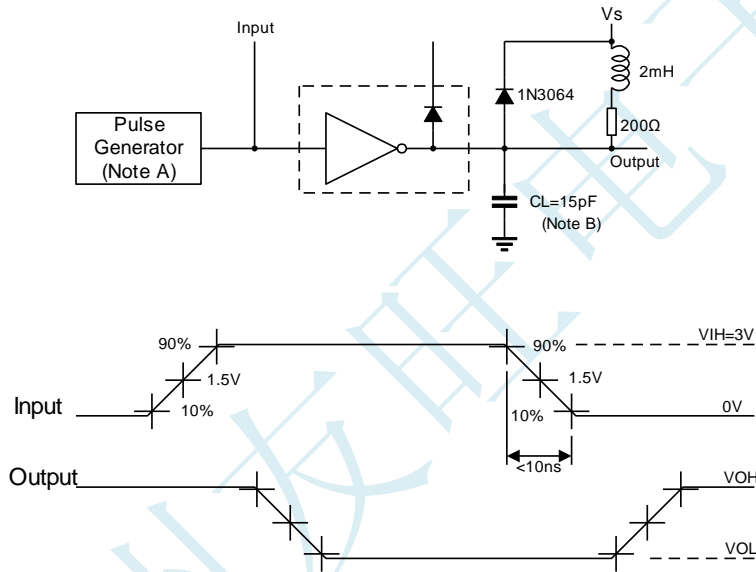


Figure 9. Propagation Delay Time Waveforms



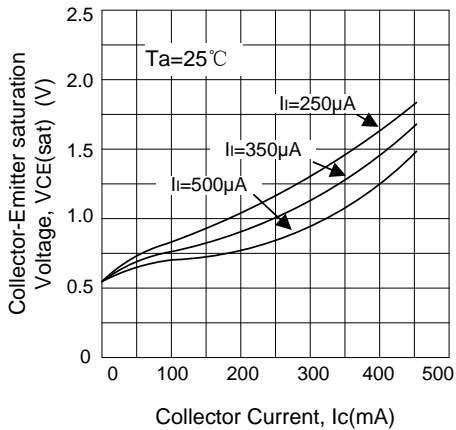
Note: A. The Pulse generator has the following characteristics: PRR=12.5kHz, $Z_o=50\Omega$

B. CL includes probe and jig capacitance.

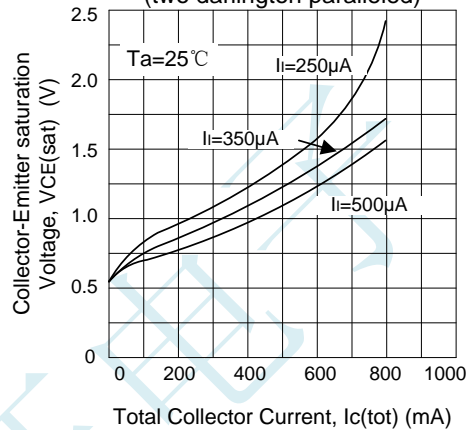
Figure 10. Latch-up Test Circuit and Voltage Waveforms

TYPICAL PERFORMANCE CHARACTERISTICS

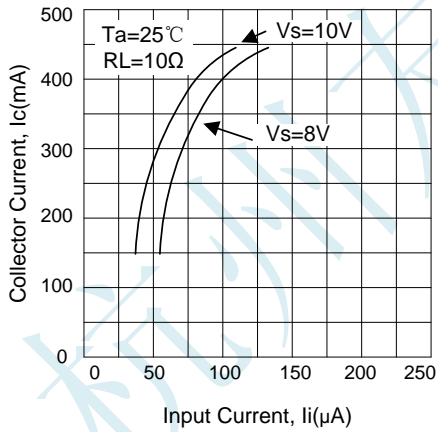
Collector-Emitter saturation Voltage vs. Collector Current



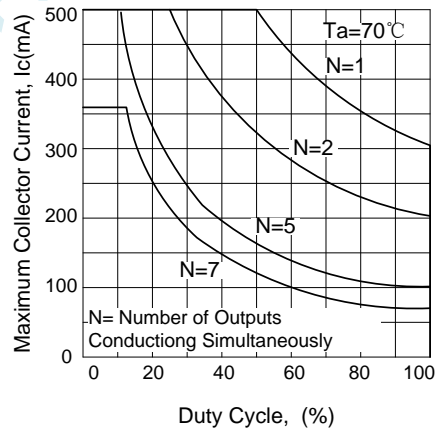
Collector-Emitter saturation Voltage vs. Total Collector Current (two darlington paralleled)



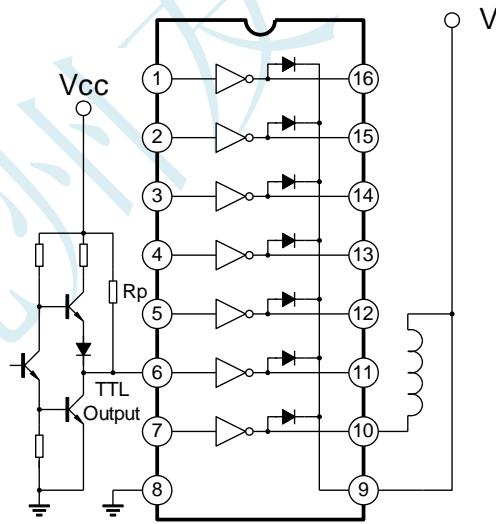
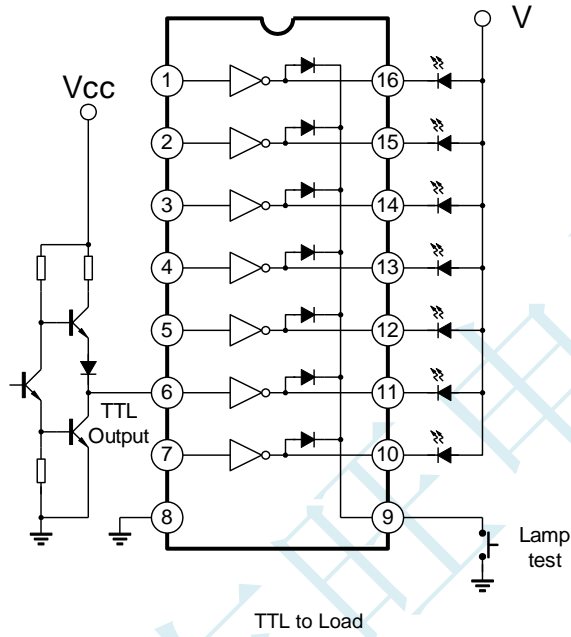
Collector Current Vs. Input Current



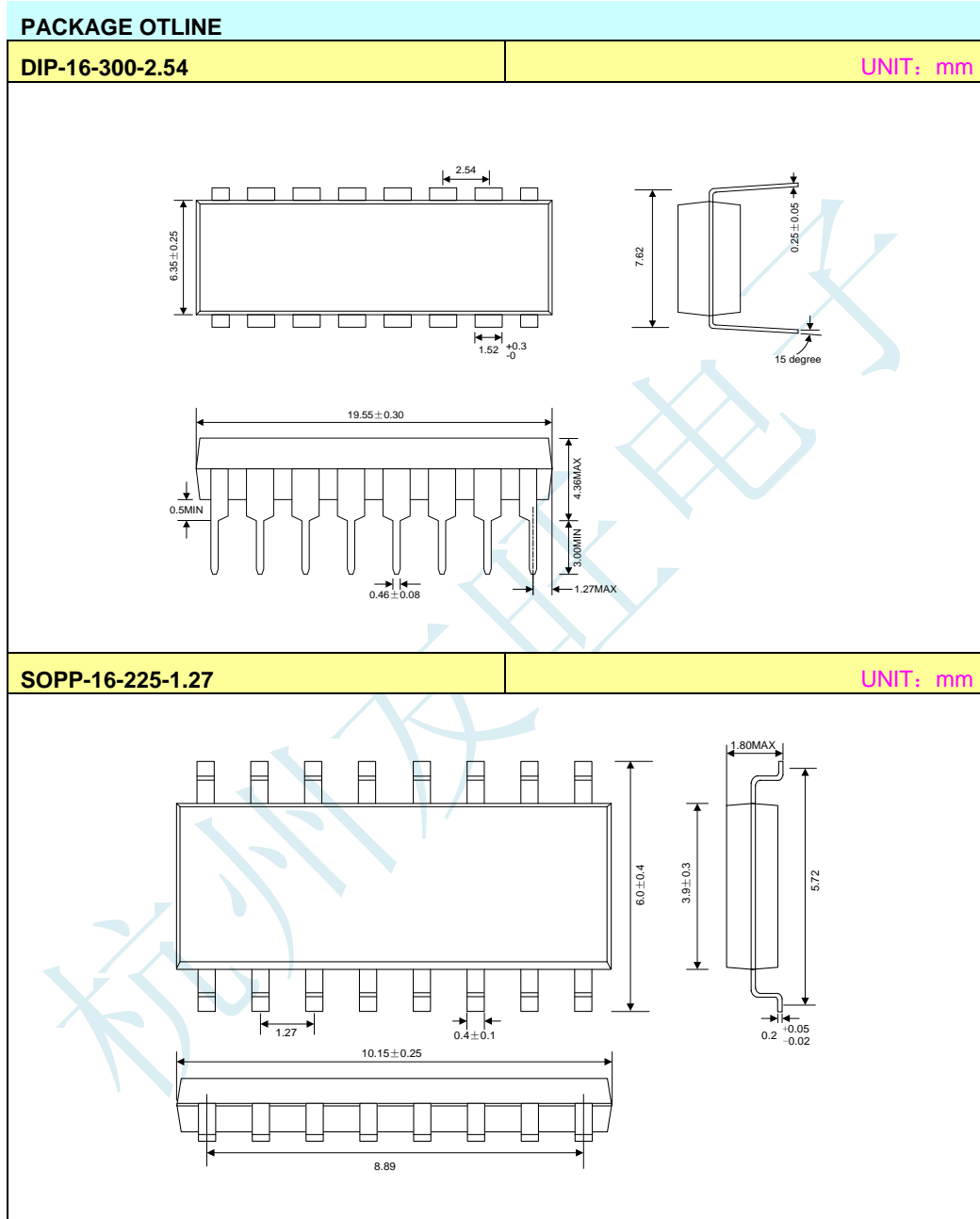
Maximum Collector Current Vs. Duty cycle



TYPICAL APPLICATION CIRCUIT



Use of pullup Resistor to increase drive Current



ELECTROSTATIC DISCHARGE CAUTION

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage handling to prevent electrostatic damage to the device.

NOTICE

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Attach